

# APPLICATION NOTE

## Definition of FIT and MTBF

A failure rate  $\lambda$  is defined by the number of failures  $r$  during a specific test time  $t$  of  $n$  components:

$$\lambda = \frac{r}{n \cdot t}$$

The unit for failure rates is 1 fit (**f**ailures **i**n **t**ime) =  $1 \cdot 10^{-9} h^{-1}$ , meaning one failure in  $10^9$  operation hours of the device.

A component specified with 100 fit is therefore expected to operate  $10^7$  hours.

Example: Testing 4000 components for 5000 hours with 2 failures in this time leads to a failure rate of

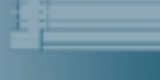
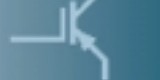
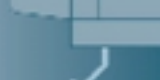
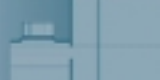
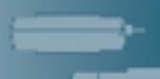
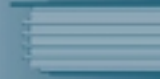
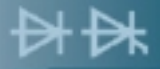
$$\lambda = \frac{2}{4000 \cdot 5000 h} = 1 \cdot 10^{-7} h^{-1} \quad \text{or expressed in fit:}$$
$$= \frac{10^{-7}}{10^{-9} h^{-1}} \text{ fit} = 100 \text{ fit}$$

The failure rate or fit value is used to calculate the MTBF (**m**ean **t**ime **b**etween **f**ailures) of a complete equipment existing of  $i$  separate components with individual failure rates  $\lambda_i$  :

$$\text{MTBF} = 1 / \sum \lambda_i$$

Example: An equipment is built of 50 components with 250 fit each, which adds up to a MTBF of  $1 / (50 \times 250 \text{ fit}) = 80.000 \text{ h}$ . The equipment is operated 18 hours a day and 300 days a year under the specified operating conditions. The expected lifetime is therefore:  $80.000 \text{ h} / (300 \cdot 18 \text{ h}) = 14.8 \text{ years}$ .

power  
the future



# FIT-RATES FOR IGBT MODULES

Together with the fit value, the operating conditions must be given. For eupec IGBT modules these conditions are: operation at 50% nominal voltage, 50% nominal current and  $T_{amb} = 40^{\circ}\text{C}$ . Tracing back shipped modules, estimated accumulated operation hours and field returns for the last years, we could calculate the following tendency in the failure rates:

power  
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